



## 2N7002BE

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### N-Channel Enhancement Mode Field Effect Transistor

#### Product Summary

$V_{DS}$	60V
$I_D$	350mA
$R_{DS(ON)}$ ( at $V_{GS}=10V$ )	1000m
$R_{DS(ON)}$ ( at $V_{GS}=4.5V$ )	14



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### Electrical Characteristics ( $T_J=25$ unless otherwise noted)

Parameter	Symbol	Conditions	Min	Typ	Max	Units
<b>Static Parameter</b>						
Drain-Source Breakdown Voltage	$BV_{DSS}$	$V_{GS}=0V, I_D=250\mu A$	60	-	-	V
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS}=60V, V_{GS}=0V$	-	-	1	$\mu A$
		$V_{DS}=60V, V_{GS}=0V, T_J=150^\circ C$	-	-	100	
Gate-Body Leakage Current	$I_{GSS}$	$V_{GS}=\pm 30V, V_{DS}=0V$	-	-	$\pm 100$	nA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D=250\mu A$	1.0	1.6	2.5	V
Static Drain-Source On-Resistance	$R_{DS(ON)}$	$V_{GS}=10V, I_D=350mA$	-	730	1000	m
		$V_{GS}=4.5V, I_D=200mA$	-	835	1400	
Diode Forward Voltage	$V_{SD}$	$I_S=350mA, V_{GS}=0V$	-	-	1.2	V



## Typical Electrical and Thermal Characteristics Diagrams

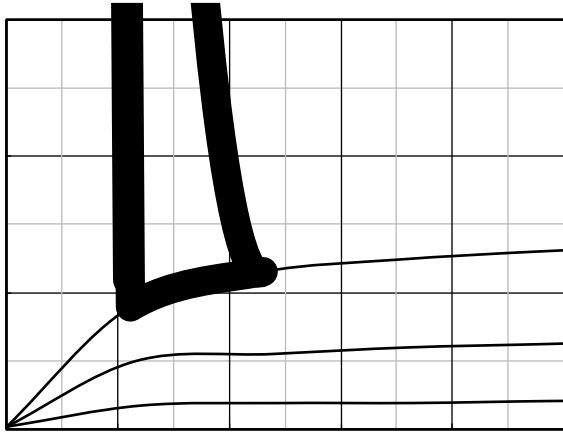


Figure 1. Output Characteristics

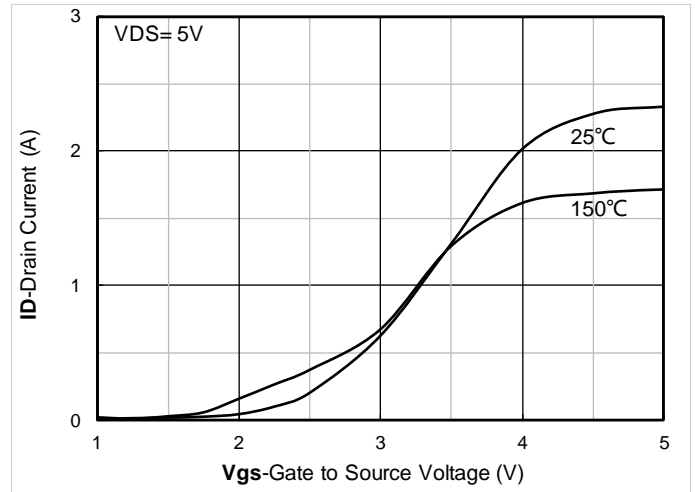


Figure 2. Transfer Characteristics

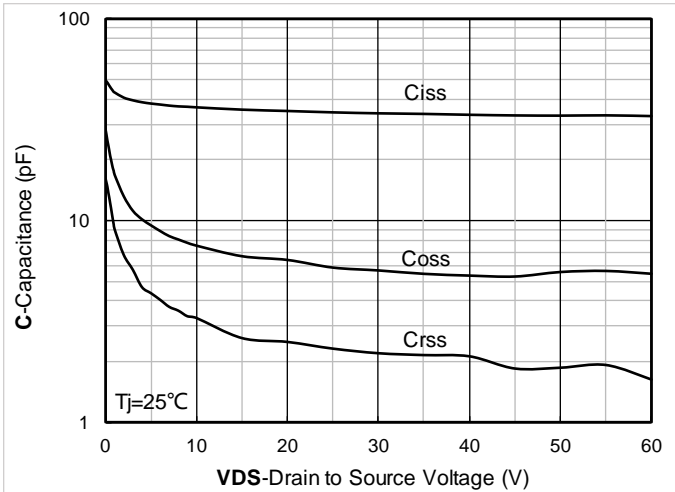


Figure 3. Capacitance Characteristics

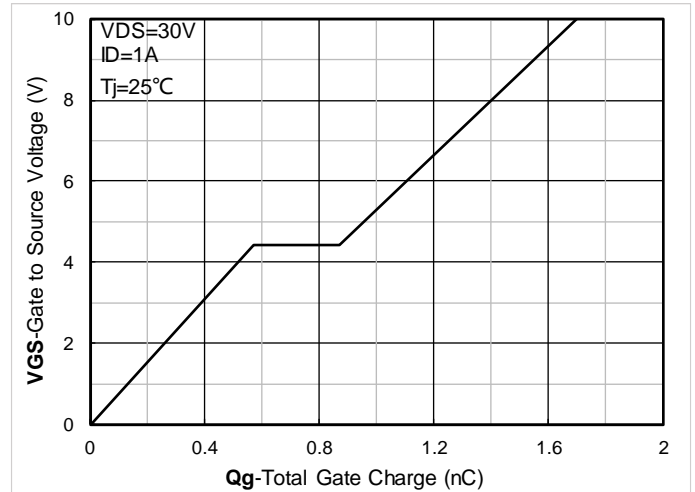


Figure 4. Gate Charge

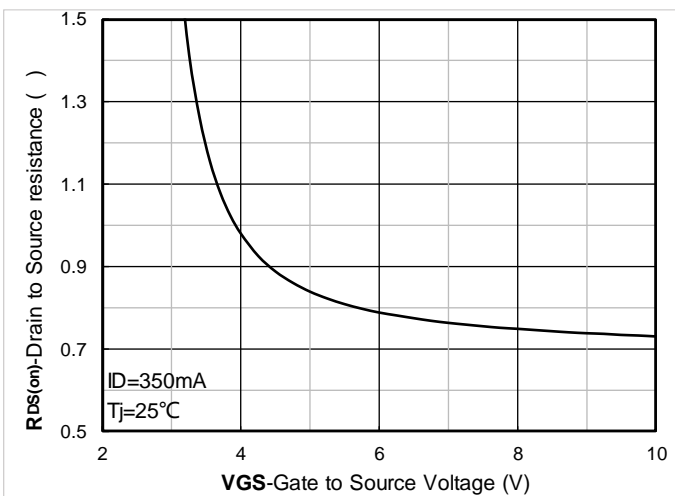


Figure 5. On-Resistance vs Gate to Source Voltage

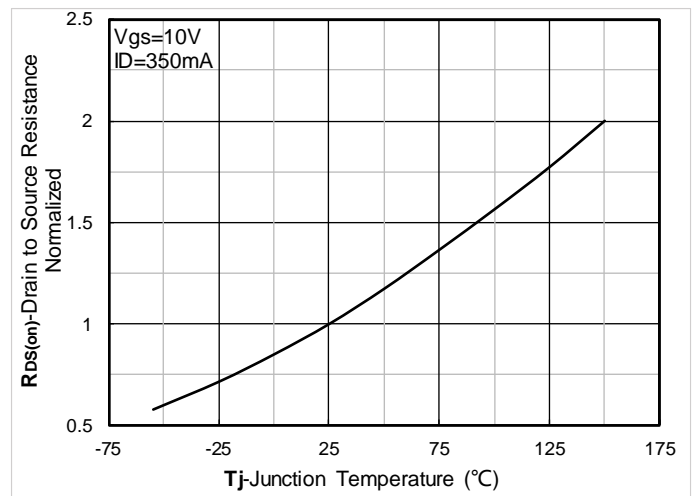


Figure 6. Normalized On-Resistance



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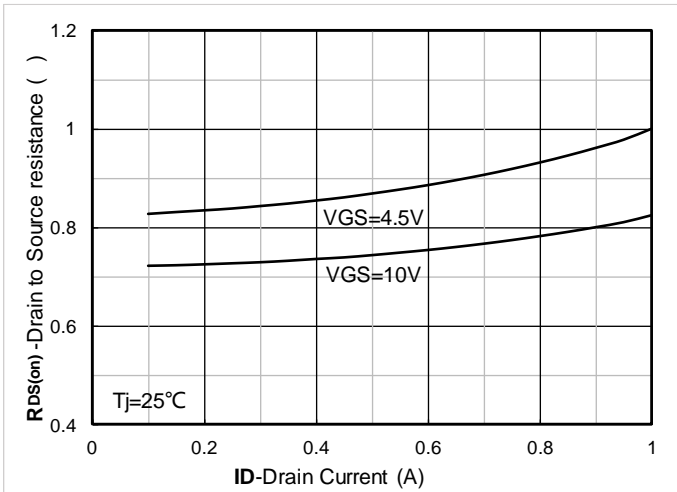


Figure 7. RDS(on) VS Drain Current

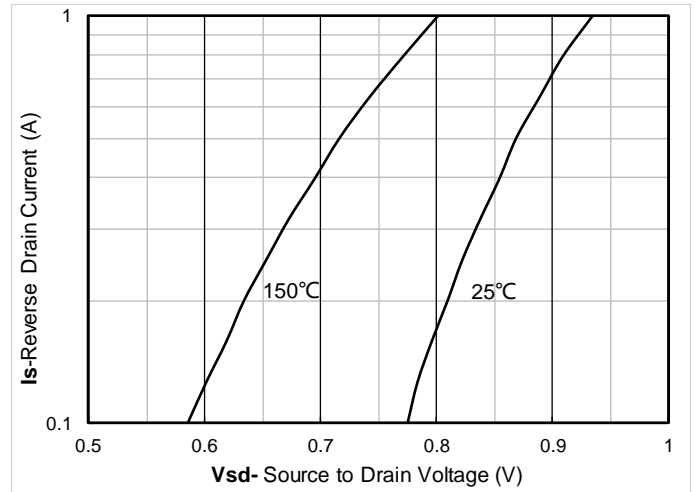


Figure 8. Forward characteristics of reverse diode

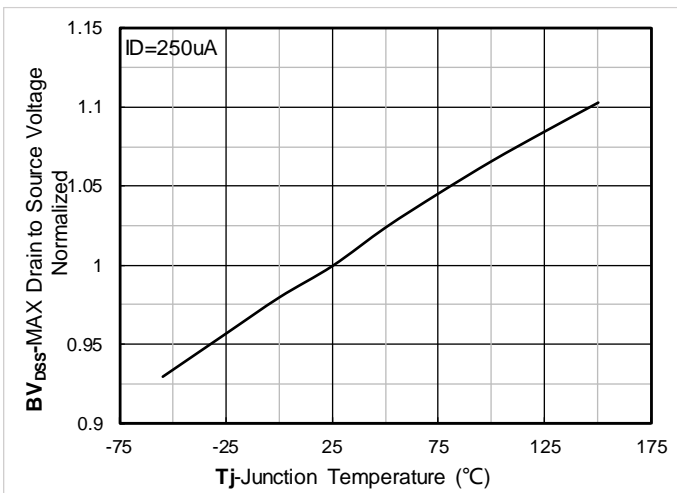


Figure 9. Normalized breakdown voltage

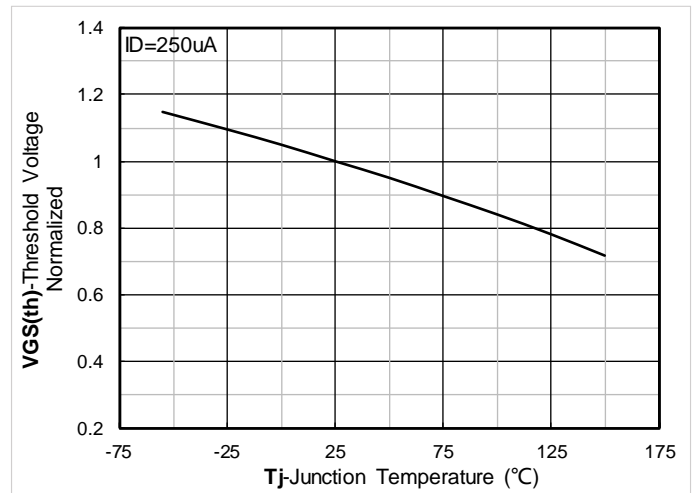


Figure 10. Normalized Threshold voltage

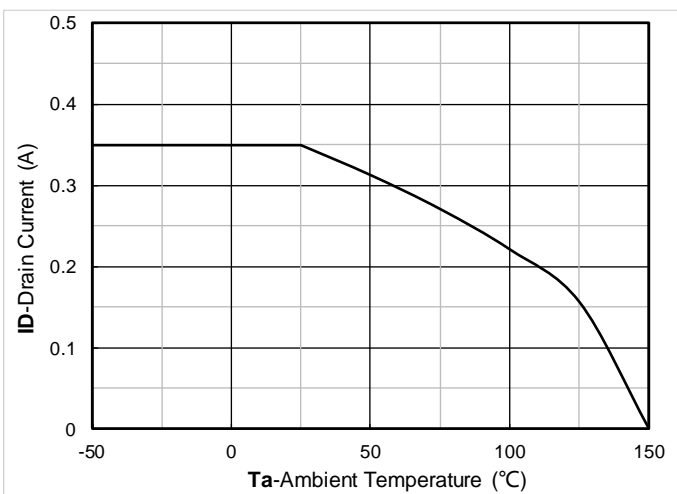


Figure 11. Current dissipation

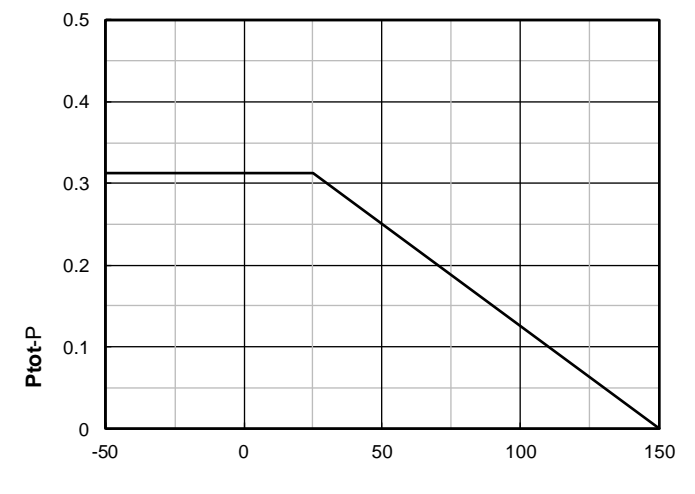


Figure 12. Power dissipation

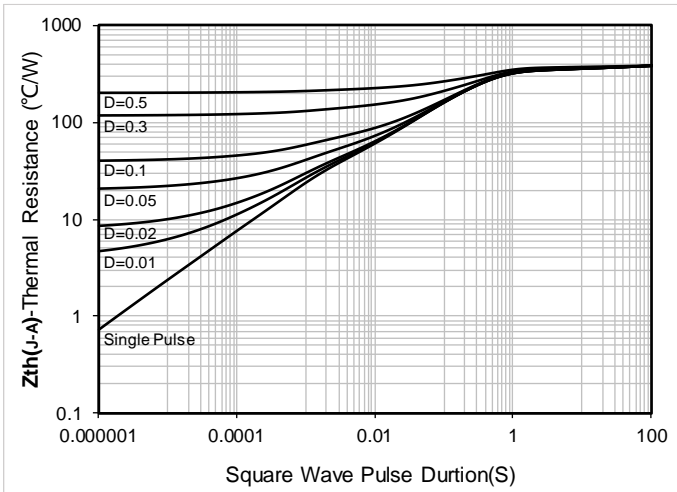


Figure 13. Maximum Transient Thermal Impedance

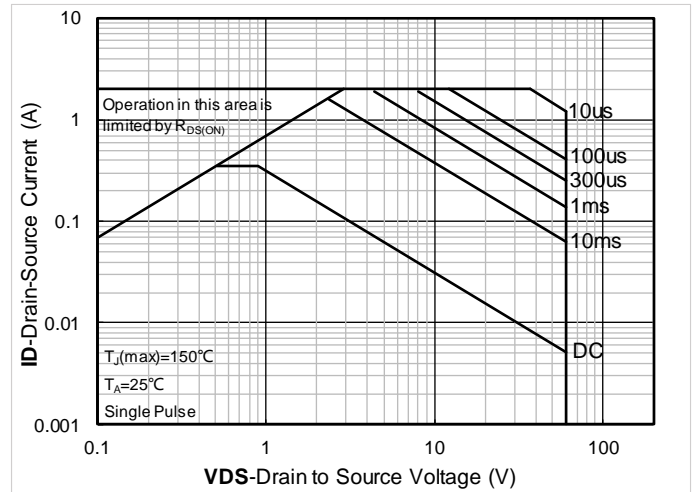


Figure 14. Safe Operation Area

## Test Circuits & Waveforms

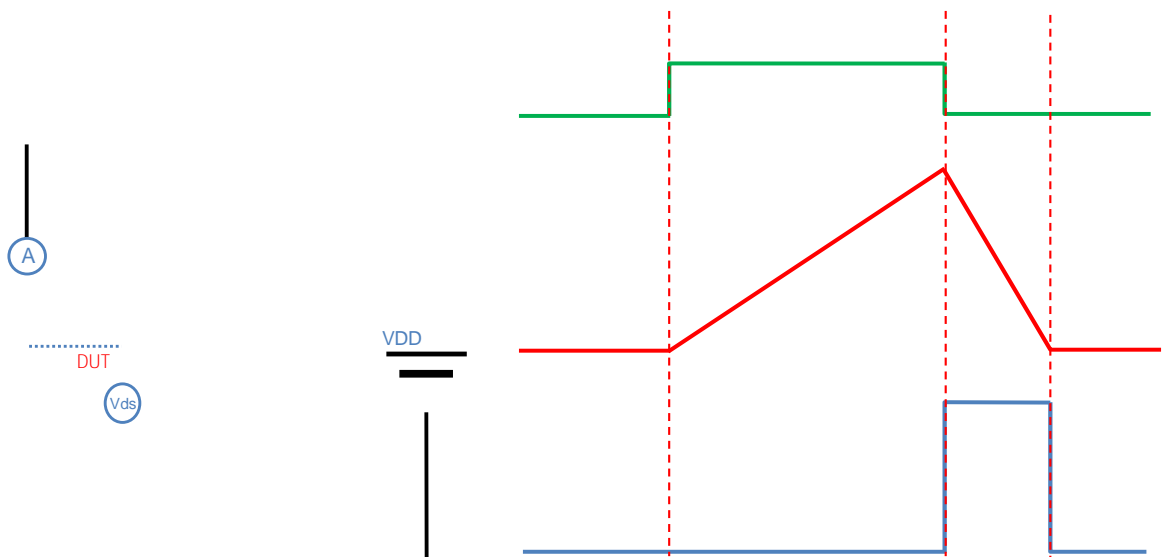


Figure A. Unclamped Inductive Switching (UIS) Test Circuit & Waveform

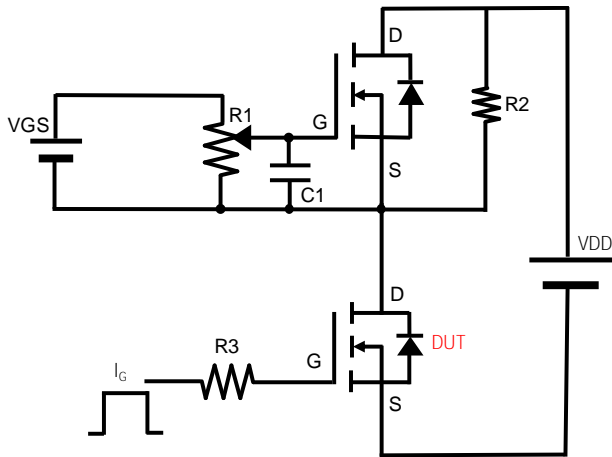


Figure B. Gate Charge Test Circuit & Waveform

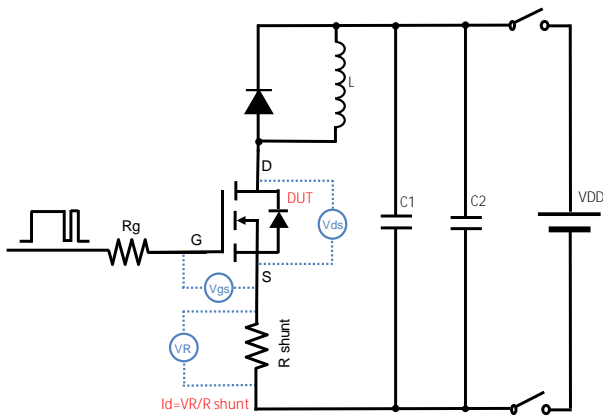


Figure C. Resistive Switching Test Circuit & Waveform

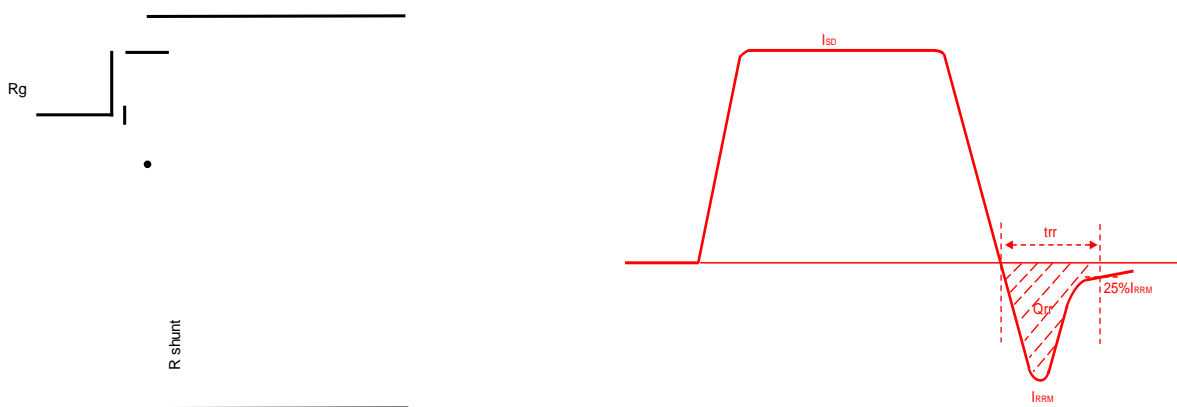
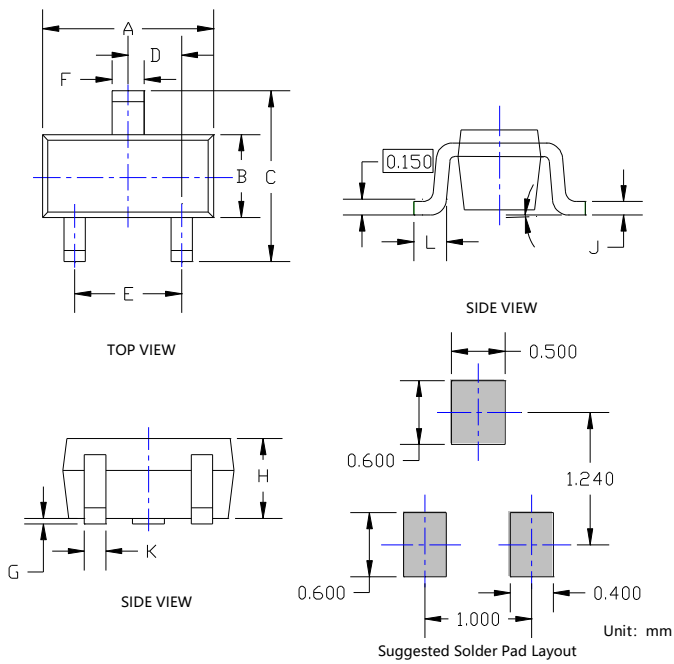


Figure D. Diode Recovery Test Circuit & Waveform



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## SOT-523 Package information



SYMBOL	DIMENSIONS			
	INCHES		Millimeter	
	MIN.	MAX.	MIN.	MAX.
A	0.059	0.067	1.500	1.700
B	0.030	0.033	0.750	0.850
C	0.057	0.069	1.450	1.750
D	0.020TYP		0.500TYP	
E	0.035	0.043	0.900	1.100
F	0.010	0.018	0.250	0.450
G	0.000	0.004	0.000	0.100
H	0.024	0.031	0.600	0.800
J	0.004	0.008	0.100	0.200
K	0.006	0.014	0.150	0.350
L	0.010	0.018	0.260	0.460
	0°	8°	0°	8°

NOTE:  
 1. PACKAGE BODY SIZES EXCLUDE MOLD FLASH AND GATE BURRS.  
 2. TOLERANCE 0.1mm UNLESS OTHERWISE SPECIFIED.  
 3. THE PAD LAYOUT IS FOR REFERENCE PURPOSES ONLY.



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